

**N&P-Channel MOSFET** 

# **General Description**

The WSP4065 is the highest performance trench N-ch and P-ch MOSFET with extreme high cell density, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The WSP4065meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

#### **Features**

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

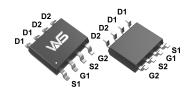
# **Product Summery**

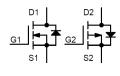
BVDSS	RDSON	ID
40V	16mΩ	10A
-40V	35mΩ	-10A

# **Applications**

- High Frequency Point-of-Load Synchronous Buck Converter.
- Networking DC-DC Power System
- Load Switch

# **SOP-8 Pin Configuration**





# **Absolute Maximum Ratings**

		Rat		
Symbol	Parameter	N-Channel	P-Channel	Units
$V_{DS}$	Drain-Source Voltage		-40	V
$V_{GS}$	Gate-Source Voltage	±20	±20	V
I <sub>D</sub> @T <sub>C</sub> =25℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	10	-10	Α
I <sub>D</sub> @T <sub>C</sub> =70℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	4.8	-4.8	Α
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>		-30	Α
EAS	EAS Single Pulse Avalanche Energy <sup>3</sup>		28	mJ
I <sub>AS</sub>	Avalanche Current		11	Α
P <sub>D</sub> @T <sub>C</sub> =25℃	Total Power Dissipation⁴		2	W
T <sub>STG</sub>	Storage Temperature Range		-55 to 150	$^{\circ}$
$T_J$	Operating Junction Temperature Range	150	150	$^{\circ}$

#### Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
R <sub>0JA</sub>	R <sub>0JA</sub> Thermal Resistance Junction-Ambient (t < 10s)		62.5	°C/W
R <sub>0JA</sub> Thermal Resistance Junction-Ambient (Steady State)			80	°C/W



# N-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	40			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25℃ , I <sub>D</sub> =1mA		0.067		V/°C
D	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =6A		16	18	m()
R <sub>DS(ON)</sub>	Static Dialii-Source On-Resistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =5A		20	22	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.5	1.9	2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>GS</sub> -V <sub>DS</sub> , I <sub>D</sub> -250uA		-5.24		mV/℃
	Drain Source Leakage Current	V <sub>DS</sub> =32V , V <sub>GS</sub> =0V , T <sub>J</sub> =85℃			1	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =32V , V <sub>GS</sub> =0V , T <sub>J</sub> =85°C			30	· uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ = $\pm 20 V$ , $V_{DS}$ = $0 V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =8A		25		S
$R_g$	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		2.5		Ω
$Q_g$	Total Gate Charge (4.5V)			19	25	
$Q_gs$	Gate-Source Charge	V <sub>DS</sub> =20V , V <sub>GS</sub> =10V , I <sub>D</sub> =6A		4.5		nC
$Q_gd$	Gate-Drain Charge			4.8		
$T_{d(on)}$	Turn-On Delay Time			8.5		
T <sub>r</sub>	Rise Time	V <sub>DD</sub> =20V , V <sub>GS</sub> =10V ,		7.2		ns
$T_{d(off)}$	Turn-Off Delay Time	$R_G=6\Omega$ , $I_D=1A$ , $R_L=20\Omega$		24		115
T <sub>f</sub>	Fall Time			5.3		
C <sub>iss</sub>	Input Capacitance			915		
Coss	Output Capacitance	V <sub>DS</sub> =20V , V <sub>GS</sub> =0V , f=1MHz		98		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			85		

# **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
I <sub>S</sub>	Continuous Source Current <sup>1,6</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			10	Α
I <sub>SM</sub>	Pulsed Source Current <sup>2,6</sup>				30	Α
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =6A,T <sub>J</sub> =25℃			1.1	V

#### Note:

- 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper, t<10sec.
- 2.The data tested by pulsed , pulse width  $\leqq 300 us$  , duty cycle  $\leqq 2\%$
- 3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =25V,  $V_{GS}$ =10V,L=0.1mH,  $I_{AS}$ =11A
- 5.The Min. value is 100% EAS tested guarantee.
- 6. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



# P-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-40			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25℃, I <sub>D</sub> =-1mA		-0.03		V/°C
D	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V , I <sub>D</sub> =-5.0A		35	39	
R <sub>DS(ON)</sub>	Static Dialii-Source Off-Resistance	$V_{GS}$ =-4.5 $V$ , $I_D$ =-4 $A$		40	50	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA	-1.3	-1.8	-2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250UA		4.56		mV/℃
	Drain Source Leakage Current	V <sub>DS</sub> =-32V , V <sub>GS</sub> =0V , T <sub>J</sub> =85℃			-1	uA
I <sub>DSS</sub>	Drain-Source Leakage Current	$V_{DS}$ =-32V , $V_{GS}$ =0V , $T_J$ =85 $^{\circ}$ C			-30	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ = $\pm 20V$ , $V_{DS}$ = $0V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-4A		15		S
$R_g$	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		8		Ω
Qg	Total Gate Charge (-4.5V)			18		
$Q_gs$	Gate-Source Charge	V <sub>DS</sub> =-20V , V <sub>GS</sub> =-10V , I <sub>D</sub> =-5.0A		4.8		nC
Q <sub>gd</sub>	Gate-Drain Charge			6.5		
T <sub>d(on)</sub>	Turn-On Delay Time			8.7		
Tr	Rise Time	V <sub>DD</sub> =-20V , V <sub>GS</sub> =-10V ,		7		
T <sub>d(off)</sub>	Turn-Off Delay Time	$R_G=6\Omega$ , $I_D=-1A$ , $R_L=20\Omega$ .		31		ns
T <sub>f</sub>	Fall Time			17		]
C <sub>iss</sub>	Input Capacitance			1105		
Coss	Output Capacitance	V <sub>DS</sub> =-20V , V <sub>GS</sub> =0V , f=1MHz		105		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			95		

# **Diode Characteristics**

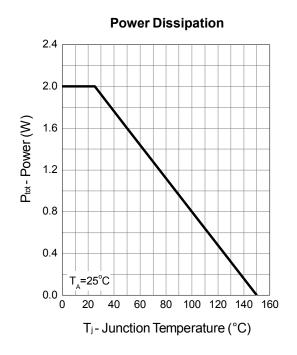
	Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
	Is	Continuous Source Current <sup>1,6</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-10	Α
ſ	I <sub>SM</sub>	Pulsed Source Current <sup>2,6</sup>				-30	Α
	$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$V_{GS}$ =0 $V$ , $I_{S}$ =-5 $A$ , $T_{J}$ =25 $^{\circ}{\mathbb{C}}$			-1.1	V

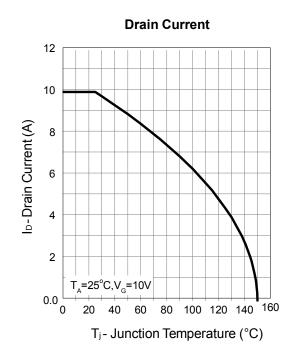
#### Note

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper,t<10sec.
- 2.The data tested by pulsed , pulse width  $\leq 300 us$  , duty cycle  $\leq 2\%$
- 3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =-25V,  $V_{GS}$ =-10V, L=0.1mH, I<sub>AS</sub>=-11A
- 4.The power dissipation is limited by 150  $^{\circ}\mathrm{C}$  junction temperature
- 5.The Min. value is 100% EAS tested guarantee.
- 6. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



# **N-Channel Typical Characteristics**

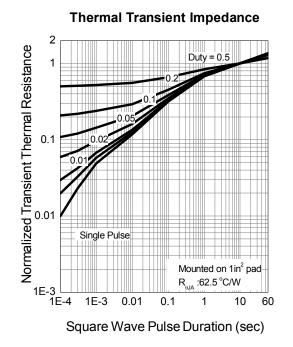




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V<sub>DS</sub> - Drain - Source Voltage (V)

Safe Operation Area

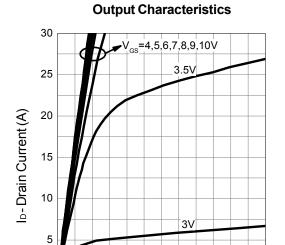




0.0

0.5

1.0



V<sub>DS</sub> - Drain - Source Voltage (V)

1.5

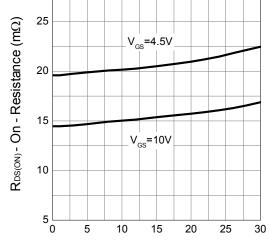
2.0

2.5

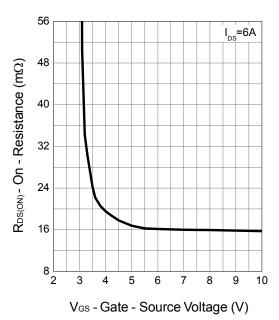
3.0

# 30 25 V<sub>GS</sub>=4.5V

**Drain-Source On Resistance** 

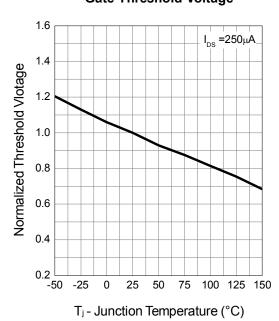


# **Gate-Source On Resistance**



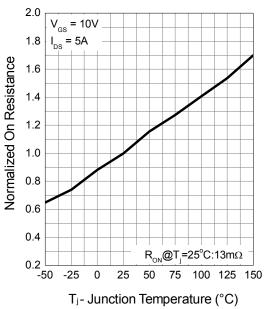
# **Gate Threshold Voltage**

ID-Drain Current (A)

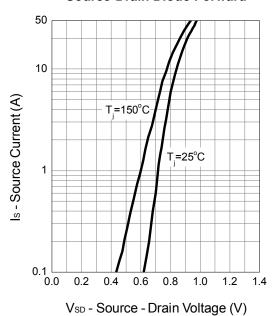




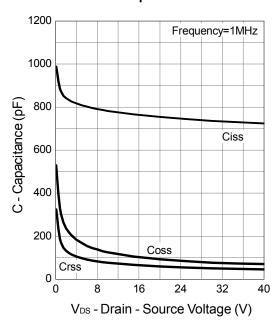
#### **Drain-Source On Resistance**



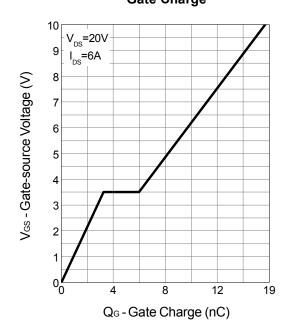
#### **Source-Drain Diode Forward**



# Capacitance

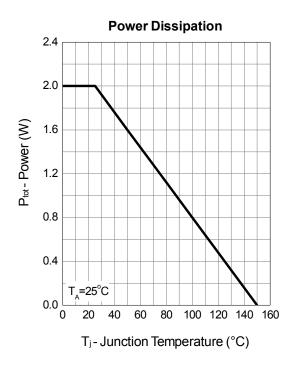


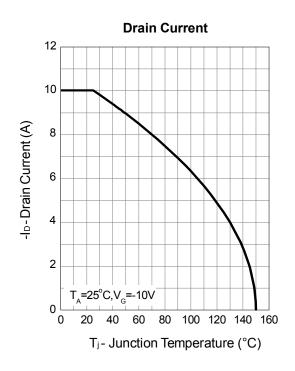
# **Gate Charge**

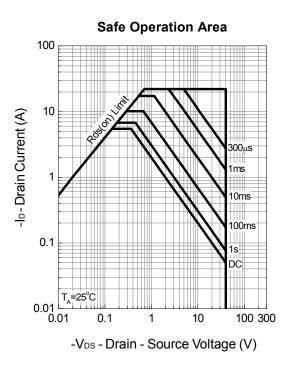


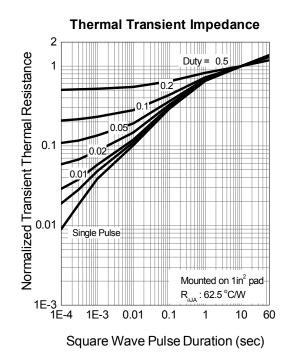


# **P-Channel Typical Characteristics**



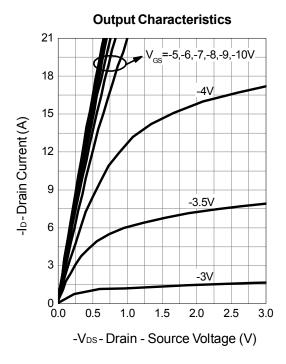


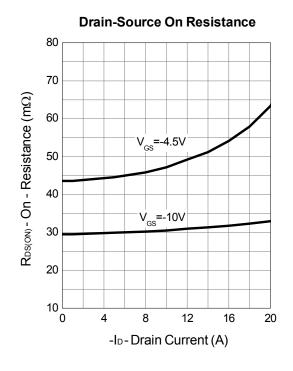


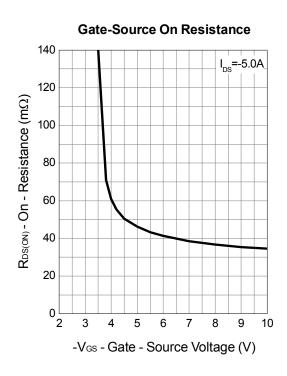


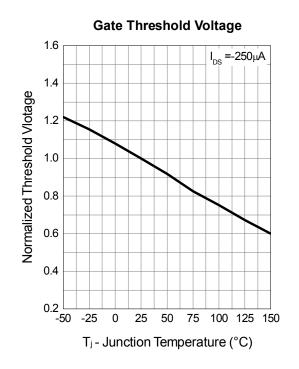




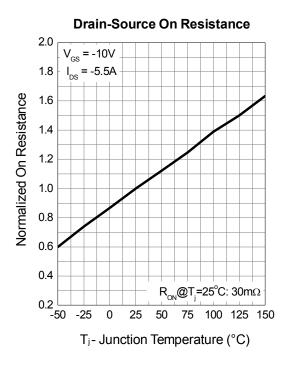


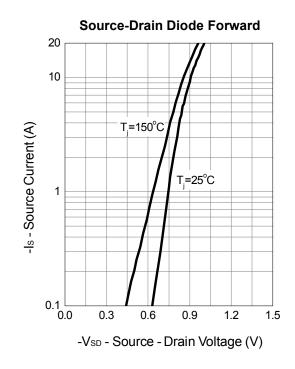


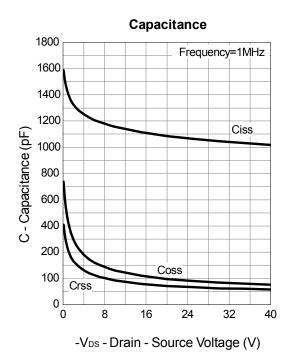


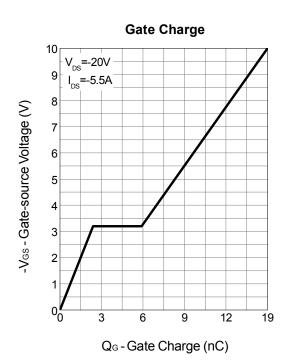














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